SCANFLEX® II BLADE 4 RMx1/2/3
Multifunctional JTAG/Boundary Scan Controller

· 1, 2 or 3 SFX II BLADE 4 in a 19″ 1HE rack

· each single controller is independent, with separate USB/LAN and power port

· high-performance controller for embedded test and programming

· outstanding flexibility through multifunctional I/O channels and FPGA instrumentation for mixed-signal and high-speed test

· high modularity and scalability through configurable TAP interface cards and additional I/O modules

· integrated compact unit controllable via USB 3.0 and GBit LAN

GÖPEL electronic
Enjoy Testing

Parameters (for one slot)

number of TAP slots	4 (independent and individually configurable with TAP plug-in card)
maximum TCK frequency	20/50/100 MHz (adjustable via software)
parallel I/O channels	64 mixed-signal channels combined with FPGA, individually configurable as Input, Output, Tri-State, via software programmable V_{10} 0.9-3.6 V (8 groups with 8 I/O)
maximum number of I/O modules	30 modules via external SFX carrier
integrated technologies	SPACE™, HYSCAN™, ADYCS™, ChipVORX®, FastScale™

BLADE 4 RMx1

BLADE 4 RMx2

BLADE 4 RMx3

SCANFLEX® II BLADE 4 RMx1/2/3
Flexible controller for embedded test and programming

High performance

· use of powerful multi-core processors and FPGAs

· simultaneous operation at up to 100 MHz on all TAPs

· operation at up to 100 MHz on I/O channels

· support for gang operations

Embedded test

· support of latest technologies such as Processor Emulation Test, FPGA Assisted Test and Embedded Diagnostics Test

· synchronization with multifunctional I/O channels and ChipVORX® FPGA instruments

Software

· integrated into Embedded JTAG Solutions platform SYSTEM CASCON™

· Plug and Play integration in 3rd party systems

· open mix of test and programming procedures in one software environment

Embedded programming

· high-speed programming of Flash components like NAND, NOR, SPI, I²C, eMMC etc. (also via I/O)

· universal programming of microcontrollers

· FPGA/PLD programming

Expandability per slot

· support of up to 30 parallel controlled SCANFLEX® I/O modules

· scalable number of one to four TAPs

· interfaces for additional debug and control components

Adaptability

· transmission over long distances of up to four meter to the target without TCK reduction or transmission problems

· software-parameterized I/O (slew rate, impedance, termination)

· via software selectable protocols (JTAG, DAP, COP, SWD, BDM, SBW, UART etc.)

: Made in Germany